

Abstract

When a redundancy circuit is provided to relieve the inferiority of a semiconductor storage device, and then, the semiconductor storage device has no defect, power is inconveniently supplied even to the unused redundancy circuit to generate unnecessary leakage current.

A self-diagnosis circuit for a semiconductor storage device is provided to perform the self-diagnosis of the semiconductor storage device upon turning on a power source. Power (2) is supplied to a redundancy circuit part and power (1) is supplied to a circuit part except the redundancy circuit part. When the semiconductor storage device has no defect as a result of the self-diagnosis, a control for turning off the power (2) of the redundancy circuit part is performed.